Se	arc	h	Note	es	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/710,703	ANDERSEN ET AL.
Examiner	Art Unit
Hai H. Huynh	3747

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SEARCHED					
Class	Subclass	Date	Examiner		
123	350	7/11/2006	ННН		
123	352	7/11/2006	ННН		
123	435-436	7/11/2006	ННН		
123	492-493	7/11/2006	ннн		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East	7/11/2006	ннн		